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Atty. Docket No.: 3600-328-01

Application No.:

10/042,549

Applicant: Christopher A. MICHALUK

Filing Date: January 9, 2002

Group Art Unit:

Not Yet Assigned

U.S. PATENT DOCUMENTS

Examiner Initial*		Document Number	Date	Name	Class	Sub Class	Filing Date If Appropriate
Aro	1	2,950,185	08/23/60	E.G. Hellier et al.	75	0.5	
Aro	2	3,767,456	10/23/73	Glaski	117	71 M	
Aro	3	3,829,310	08/13/74	T.X. Mahy	75	0.5 BB	
Aro	4	4,149,876	04/17/79	Rerat	75	0.5 BB	
Aro	5	4,684,399	08/04/87	Bergman et al.	75	0.5	
Aro	6	5,234,491	08/10/93	Chang	75	622	
Aro	7	5,242,481	09/07/93	Kumar	75	364	
Aro	8	6,193,821	02/27/01	Zhang	148	668	
Aro	9	2001/0001401	05/24/01	Segal	148	670	

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Sub Class	Translation Yes or No
Aro	10	WO 00/31310	06/02/00	WIPO	—	—	Yes

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

Aro	Kirk-Othmer, Encyclopedia of Chemical Technology, 3rd Edition, Vol. 22, pp. 541-564, 1983
Aro	S.I. Wright, G.T. Gray, and A.D. Rollett, <i>Textural and Microstructural Gradient Effects on the Mechanical Behavior of a Tantalum Plate</i> , Metallurgical and Materials Transactions A, 25A, pp. 1025-1031, 1994.
Aro	C.A. Michaluk, R.O. Burt, and D.P. Lewis, <i>Tantalum 101: Economics and Technology of Ta Materials</i> , Semiconductor International, Vol. 23, No. 8, pp. 271-278, 2000.
Aro	C.A. Michaluk, <i>Correlating Discrete Orientation and Grain Size to the Sputter Deposition Properties of Tantalum</i> , Journal of Electronic Materials, Vol. 31, No. 1, pp. 2-9, 2002.

Examiner

Date Considered

4/22/03

*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609, draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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FORM PTO-1449 (REV 7-80)		Atty. Docket No. CPM0029CIP(3600-328-01)
Application No. 10/042,549		
INFORMATION DISCLOSURE STATEMENT		
APPLICANT: Christopher A. MICHALUK		
Filing Date: January 9, 2002		Group Art Unit: 1742

U.S. PATENT DOCUMENTS

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FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION YES	NO
Aro	WO 01/96620	12/20/01	WIPO	C22B			
Aro	WO 99/61670	12/2/99	WIPO	C22B	34/24		
Aro	WO 99/66100	12/23/99	WIPO	C23C	14/34		

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>Arc</i>	G. I. Friedman, "Grain Size Refinement in a Tantalum Ingot", Metallurgical Transactions., vol. 2, January 1971(1971-01), pages 337-341, XP002227180 METALLURGICAL SOCIETY OF AIME. NEW YORK., US. Page 337, column 1, line 1-page 340, column 2, line 28; table 4.
<i>Arc</i>	S. R. Lampman et al., "Metals Handbook, Vol 2", 1990 ASM INTERNATIONAL, Ohio, US XP002227181, "Niobium", Gerardi. page 565-574.
<i>Arc</i>	International Search Report for PCT/US02/23640, January 23, 2003

EXAMINER

DATE CONSIDERED

4/22/02

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